

Notice of References Cited

Application/Control No.

09/681,186

Applicant(s)/Patent Under
Reexamination
SCHNEIDER ET AL.

Examiner

Chih-Cheng Glen Kao

Art Unit

2882

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	X	Levine et al., Tomographic reconstruction of an integrated circuit interconnect, Applied Physics Letters, January 4, 1999, Vol. 74, No. 1, pps 150-152.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.